S	Search Notes	•

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/801,011	BONNET ET AL.	
Examiner	Art Unit	
Anthony Weier	1761 .	

	SEARCHED			
Class	Subclass	Date	Examiner	
426	422, 599	7/15/2005	AW	
		25		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
Inventor Search		7/15/2005	AW
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